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|-----------------------------------|--|-------------------------|---|-------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination | |
| | | 10/557,197 | YAMAMICHI ET AL. | |
| Examiner | | Art Unit | | Page 1 of 1 |
| SON T. HOANG | | 2165 | | |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|-----|--|-----------------|--------------------------|----------------|
| * | A | US-2002/0165987 | 11-2002 | Arisaka et al. | 709/246 |
| * | B | US-2002/0059120 | 05-2002 | Milton, James K. | 705/28 |
| * | C | US-2003/0236695 | 12-2003 | Litwin, Louis Robert JR. | 705/10 |
| * | D | US-2002/0023000 | 02-2002 | Bollay, Denison W. | 705/14 |
| * | E | US-2003/0140348 | 07-2003 | Stewart, John Sidney | 725/101 |
| * | F | US-2002/0007457 | 01-2002 | Neff, C. Andrew | 713/180 |
| * | G | US-6,384,861 | 05-2002 | Lindsey, Todd D. | 348/169 |
| * | H | US-5,832,171 | 11-1998 | Heist, H. Daniel | 386/46 |
| I | US- | | | | |
| J | US- | | | | |
| K | US- | | | | |
| L | US- | | | | |
| M | US- | | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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